

The paragraph beginning on page 38, line 9 has been rewritten to read as follows:

--As shown in Fig. 23b, the auxiliary line 500 is formed from the same metal as that used to form the gate bus lines on the TFT substrate 200 which is a glass substrate at the same time when the gate bus lines 218 are formed. The auxiliary line 500 forms a multi-layer structure in combination with the drain bus lines 220 with a gate insulation film interposed therebetween, and it is electrically insulated from the drain bus lines 220 and is in an electrically floating state in which it does not work as it is.--

In the Claims:

Please amend Claims 1-5 and add new Claims 6-11 to read as follows:

1. (Once Amended) A method for repairing a defect in a display having pixel regions formed on a substrate, comprising the step of:
B6 irradiating a multi-layer region, formed by stacking a plurality of conductive layers with an insulation layer interposed between each of the conductive layers, with a laser beam to selectively remove only an upper conductive layer of said multi-layer region, without removing any portions of the conductive layer, or layers, located below the portion of the upper conductive layer being removed, such that neither inter-layer short-circuit nor short-circuit in a single layer occurs in said multi-layer region.

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2. (Twice Amended) A method for repairing a defect in a display having pixel regions formed on a substrate, comprising the step of:

irradiating a multi-layer region, formed by stacking a plurality of conductive layers with insulation layers interposed therebetween, with a laser beam to remove said plurality of conductive layers, stacked above each other, in said multi-layer region such that no inter-layer short-circuit occurs.

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3. (Once Amended) A method for repairing a defect in a display having pixel regions formed on a substrate, comprising the step of:

forming a bypass for a broken portion of a gate bus line by separating or connecting said gate bus line from or to a drain electrode or a source electrode of a TFT or a pixel electrode or a storage capacitor bus line which is formed with an insulation film interposed through local irradiation with a laser beam, thereby allowing said broken portion to be repaired by sacrificing regular use of an associated pixel.

4. (Once Amended) A display having a plurality of bus lines formed in a display area, comprising:

said plurality of bus lines each being defined by three segments, a display area segment, an extraction wiring portion segment, and a terminal portion segment, where said extraction wiring portion segment is positioned between said display area segment and said terminal portion segment; and

a repair line connectable to a plurality of extraction lines, at said display area segments and said terminal portion segments, but not at said extraction wiring portion segments, said repair line being configured for repairing a line breakage that has occurred in at least one of said extraction wiring portion segments.

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5. (Twice Amended) A display having a plurality of bus lines formed in a display area, comprising:

an auxiliary line formed along said bus line in an extraction wiring portion via an insulation film for repairing a line breakage that has occurred at the extraction wiring portion;

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wherein said auxiliary line and said bus line each include a widened portion, wherein said widened portions are stacked to form a pad that is situated at an intermediate portion of said bus line.

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6. (New Claim) A method for repairing a defect in a display having pixel regions formed on a substrate, comprising the step of:

forming a bypass for a broken portion of a gate bus line by forming an alternate conductive path through a pixel electrode, whereby regular use of an associated pixel is sacrificed.

7. (New Claim) The method according to Claim 6, further comprising the steps of:

creating a first electrically isolated line on a portion of a storage capacitor bus line, wherein said storage capacitor bus line is adjacent to said gate bus line, and further wherein said storage capacitor bus line is separated from said gate bus line by said pixel being sacrificed;

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creating a second electrically isolated line on a portion of a drain bus line; and forming said bypass by using local irradiation with a laser beam, said bypass consisting of a conductive path that includes a first edge of said broken gate bus line, a source electrode, said pixel being sacrificed, said first electrically isolated line, said second electrically isolated line, and a second edge of said broken gate bus line.

8. (New Claim) The method according to Claim 7, wherein said conductive path also includes a drain electrode that is positioned adjacent said second edge of said broken gate bus line.

9. (New Claim) A method for repairing a defect in a display having pixel regions, comprising the step of:

forming a bypass for a broken portion of a gate bus line by forming an alternate conductive path around a pixel electrode, whereby regular use of an associated pixel is sacrificed.

10. (New Claim) The method according to Claim 9, further comprising the steps of:

creating a first electrically isolated line on a portion of a first drain bus line that is adjacent to said pixel being sacrificed;

creating a second electrically isolated line on a portion of a storage capacitor bus line, wherein said storage capacitor bus line is adjacent to said gate bus line, and further wherein said storage capacitor bus line is separated from said gate bus line by said pixel being sacrificed;

creating a third electrically isolated line on a portion of a second drain bus line that is both adjacent to said pixel being sacrificed and located on an opposite side of said pixel being sacrificed than said first drain bus line; and

forming said bypass by using local irradiation with a laser beam, said bypass consisting a conductive path that includes a first edge of said broken gate bus line, said first electrically isolated line, said second electrically isolated line, said third electrically isolated line and a second edge of said broken gate bus line.

11. (New Claim) The method according to Claim 10, further comprising the steps of:

irradiating with a laser beam to form an additional cut on said first drain bus line to ensure isolation of first electrically isolated line; and

irradiating with a laser beam to form a second additional cut on said second drain bus line to ensure isolation of said third electrically isolated line.

12. (New Claim) A display having a plurality of bus lines formed in a display area, comprising:

an auxiliary line, formed along said bus line in an extraction wiring portion via an insulation film, for repairing a line breakage that has occurred at the extension wiring portion;

wherein a terminal end portion of said auxiliary line is electrically connected to a terminal end portion of bus line via contact holes, whereby repair of a broken portion of said bus line may be accomplished by using laser irradiation to make only a single additional electrical connection between said auxiliary line and said bus line.

REMARKS

Attached hereto is a marked-up version of the changes made to the specification and claims by the current amendment. The attached Appendix is captioned "Version with markings to show changes made."

As a preliminary matter, Applicants respectfully request an indication that the Examiner considered the IDS filed on July 27, 2000.

As an additional preliminary matter, with regard to the drawings, Applicants have included herewith a marked-up copy of Figure 30, with the proposed changes in red.